



<b>Membership</b>	<b>Publications/Services</b>	<b>Standards</b>	<b>Conferences</b>	<b>Careers/Jobs</b>
-------------------	------------------------------	------------------	--------------------	---------------------

**IEEE Xplore®**  
RELEASE 1.7

Welcome  
United States Patent and Trademark Office

[Help](#) [FAQ](#) [Terms](#) [IEEE Peer Review](#)

## Quick Links



» Se.

**Welcome to IEEE Xplore®**

- Home
- What Can I Access?
- Log-out

## Tables of Contents

- ☐ Journals & Magazines
- ☐ Conference Proceedings
- ☐ Standards

## Search

- ☐ By Author  
☐ Basic  
☐ Advanced

## Member Services

- Join IEEE
- Establish IEEE Web Account
- Access the IEEE Member Digital Library

Your search matched **0** of **1034807** documents.

A maximum of **500** results are displayed, **15** to a page, sorted by **Relevance Descending** order.

### Refine This Search:

You may refine your search by editing the current search expression or entering new one in the text box.

```
materializ*<paragraph>view <paragraph>tuple<and>clu
```

**Search**

☐ Check to search within this result set

### Results Key:

**JNL** = Journal or Magazine    **CNF** = Conference    **STD** = Standard

### Results:

**No documents matched your query.**

 **Print Format**

[Home](#) | [Log-out](#) | [Journals](#) | [Conference Proceedings](#) | [Standards](#) | [Search by Author](#) | [Basic Search](#) | [Advanced Search](#) | [Join IEEE](#) | [Web Account](#) | [New this week](#) | [OPAC Linking Information](#) | [Your Feedback](#) | [Technical Support](#) | [Email Alerting](#) | [No Robots Please](#) | [Release Notes](#) | [IEEE Online Publications](#) | [Help](#) | [FAQ](#) | [Terms](#) | [Back to Top](#)

Copyright © 2004 IEEE — All rights reserved

IEEE HOME | SEARCH IEEE | SHOP | WEB ACCOUNT | CONTACT IEEE


[Membership](#) [Publications/Services](#) [Standards](#) [Conferences](#) [Careers/Jobs](#)
**IEEE Xplore®**  
RELEASE 1.7

 Welcome  
United States Patent and Trademark Office

[Help](#) [FAQ](#) [Terms](#) [IEEE Peer Review](#)
[Quick Links](#)

Welcome to IEEE Xplore®

- ☐ Home
- ☐ What Can I Access?
- ☐ Log-out

Tables of Contents

- ☐ Journals & Magazines
- ☐ Conference Proceedings
- ☐ Standards

Search

- ☐ By Author
- ☐ Basic
- ☐ Advanced

Member Services

- ☐ Join IEEE
- ☐ Establish IEEE Web Account
- ☐ Access the IEEE Member Digital Library

Print Format

Your search matched **5** of **1034807** documents.A maximum of **500** results are displayed, **15** to a page, sorted by **Relevance Descending** order.**Refine This Search:**

You may refine your search by editing the current search expression or enter a new one in the text box.

☐ Check to search within this result set**Results Key:****JNL** = Journal or Magazine   **CNF** = Conference   **STD** = Standard**1 Detecting and representing relevant Web deltas in WHOWEDA***Bhowmick, S.S.; Madria, S.K.; Wee Keong Ng;*Knowledge and Data Engineering, IEEE Transactions on , Volume: 15 , Issue: 2 , March-April 2003  
Pages:423 - 441[\[Abstract\]](#)   [\[PDF Full-Text \(2779 KB\)\]](#)   **IEEE JNL****2 Updating distributed materialized views***Segev, A.; Park, J.;*Knowledge and Data Engineering, IEEE Transactions on , Volume: 1 , Issue: 2 , June 1989  
Pages:173 - 184[\[Abstract\]](#)   [\[PDF Full-Text \(1128 KB\)\]](#)   **IEEE JNL****3 Practical lineage tracing in data warehouses***Cui, Y.; Widom, J.;*Data Engineering, 2000. Proceedings. 16th International Conference on , 29 March 2000  
Pages:367 - 378[\[Abstract\]](#)   [\[PDF Full-Text \(192 KB\)\]](#)   **IEEE CNF****4 Concurrent maintenance of views using multiple versions***Kulkarni, S.; Mohania, M.;*Database Engineering and Applications, 1999. IDEAS '99. International Symp Proceedings , 2-4 Aug. 1999  
Pages:254 - 258

[\[Abstract\]](#) [\[PDF Full-Text \(52 KB\)\]](#) IEEE CNF

---

**5 Maintaining materialized views in distributed databases**

*Segev, A.; Park, J.;*

Data Engineering, 1989. Proceedings. Fifth International Conference on , 6-10 1989

Pages:262 - 270

[\[Abstract\]](#) [\[PDF Full-Text \(720 KB\)\]](#) IEEE CNF

---

[Home](#) | [Log-out](#) | [Journals](#) | [Conference Proceedings](#) | [Standards](#) | [Search by Author](#) | [Basic Search](#) | [Advanced Search](#) | [Join IEEE](#) | [Web Account](#) | [New this week](#) | [OPAC Linking Information](#) | [Your Feedback](#) | [Technical Support](#) | [Email Alerting](#) | [No Robots Please](#) | [Release Notes](#) | [IEEE Online Publications](#) | [Help](#) | [FAQ](#) | [Terms](#) | [Back to Top](#)

Copyright © 2004 IEEE — All rights reserved

IEEE HOME | SEARCH IEEE | SHOP | WEB ACCOUNT | CONTACT IEEE


[Membership](#) | [Publications/Services](#) | [Standards](#) | [Conferences](#) | [Careers/Jobs](#)
**IEEE Xplore®**  
 RELEASE 1.7

 Welcome  
 United States Patent and Trademark Office

[Help](#) | [FAQ](#) | [Terms](#) | [IEEE Peer Review](#)
[Quick Links](#)

Welcome to IEEE Xplore®

- ☐ Home
- ☐ What Can I Access?
- ☐ Log-out

Tables of Contents

- ☐ Journals & Magazines
- ☐ Conference Proceedings
- ☐ Standards

Search

- ☐ By Author
- ☐ Basic
- ☐ Advanced

Member Services

- ☐ Join IEEE
- ☐ Establish IEEE Web Account
- ☐ Access the IEEE Member Digital Library

Print Format

[Home](#) | [Log-out](#) | [Journals](#) | [Conference Proceedings](#) | [Standards](#) | [Search by Author](#) | [Basic Search](#) | [Advanced Search](#) | [Join IEEE](#) | [Web Account](#) | [New this week](#) | [OPAC Linking Information](#) | [Your Feedback](#) | [Technical Support](#) | [Email Alerting](#) | [No Robots Please](#) | [Release Notes](#) | [IEEE Online Publications](#) | [Help](#) | [FAQ](#) | [Terms](#) | [Back to Top](#)
Your search matched **0** of **1034807** documents.A maximum of **500** results are displayed, **15** to a page, sorted by **Relevance Descending** order.**Refine This Search:**

You may refine your search by editing the current search expression or entering a new one in the text box.

☐ Check to search within this result set**Results Key:****JNL** = Journal or Magazine   **CNF** = Conference   **STD** = Standard**Results:****No documents matched your query.**

IEEE HOME | SEARCH IEEE | SHOP | WEB ACCOUNT | CONTACT IEEE



Membership Publications/Services Standards Conferences Careers/Jobs

**IEEE Xplore®**  
 RELEASE 1.7

 Welcome  
 United States Patent and Trademark Office

[Help](#) [FAQ](#) [Terms](#) [IEEE Peer Review](#)
[Quick Links](#)

Welcome to IEEE Xplore®

- ☐ Home
- ☐ What Can I Access?
- ☐ Log-out

Tables of Contents

- ☐ Journals & Magazines
- ☐ Conference Proceedings
- ☐ Standards

Search

- ☐ By Author
- ☐ Basic
- ☐ Advanced

Member Services

- ☐ Join IEEE
- ☐ Establish IEEE Web Account
- ☐ Access the IEEE Member Digital Library

Print Format

Your search matched **2** of **1034807** documents.A maximum of **500** results are displayed, **15** to a page, sorted by **Relevance Descending** order.**Refine This Search:**

You may refine your search by editing the current search expression or enter a new one in the text box.

(materializ\*&lt;near&gt;view)&lt;and&gt; node&lt;and&gt;(cluster\*&lt;or&gt;

☐ Check to search within this result set
**Results Key:****JNL** = Journal or Magazine **CNF** = Conference **STD** = Standard
**1 Scheduling the allocation of data fragments in a distributed database environment: a machine learning approach**
*Chaturvedi, A.R.; Choubey, A.K.; Jinsheng Roan;*

Engineering Management, IEEE Transactions on , Volume: 41 , Issue: 2 , May

Pages:194 - 207

[\[Abstract\]](#) [\[PDF Full-Text \(1148 KB\)\]](#) **IEEE JNL**
**2 Data warehouse clustering on the Web**
*Triantafillakis, A.; Kanellis, P.; Martakos, D.;*

Database and Expert Systems Applications, 2002. Proceedings. 13th International Workshop on , 2-6 Sept. 2002

Pages:800 - 804

[\[Abstract\]](#) [\[PDF Full-Text \(265 KB\)\]](#) **IEEE CNF**
[Home](#) | [Log-out](#) | [Journals](#) | [Conference Proceedings](#) | [Standards](#) | [Search by Author](#) | [Basic Search](#) | [Advanced Search](#) | [Join IEEE](#) | [Web Account](#) | [New this week](#) | [OPAC Linking Information](#) | [Your Feedback](#) | [Technical Support](#) | [Email Alerting](#) | [No Robots Please](#) | [Release Notes](#) | [IEEE Online Publications](#) | [Help](#) | [FAQ](#) | [Terms](#) | [Back to Top](#)

Copyright © 2004 IEEE — All rights reserved

IEEE HOME | SEARCH IEEE | SHOP | WEB ACCOUNT | CONTACT IEEE



» Se

Membership Publications/Services Standards Conferences Careers/Jobs

**IEEE Xplore®**  
 RELEASE 1.7

 Welcome  
 United States Patent and Trademark Office

[Help](#) [FAQ](#) [Terms](#) [IEEE Peer Review](#)
[Quick Links](#)

Welcome to IEEE Xplore®

- ☐ Home
- ☐ What Can I Access?
- ☐ Log-out

Tables of Contents

- ☐ Journals & Magazines
- ☐ Conference Proceedings
- ☐ Standards

Search

- ☐ By Author
- ☐ Basic
- ☐ Advanced

Member Services

- ☐ Join IEEE
- ☐ Establish IEEE Web Account
- ☐ Access the IEEE Member Digital Library

Print Format

Your search matched **5** of **1037503** documents.A maximum of **500** results are displayed, **15** to a page, sorted by **Relevance Descending** order.**Refine This Search:**

You may refine your search by editing the current search expression or enter a new one in the text box.

(material\*&lt;near&gt;view)&lt;paragraph&gt;(auxiliar\*&lt;near&gt;rela

☐ Check to search within this result set
**Results Key:****JNL** = Journal or Magazine **CNF** = Conference **STD** = Standard**1 Efficient maintenance of temporal data warehouses***de Amo, S.; Alves, M.H.F.;*

Database Engineering and Applications Symposium, 2000 International , 18-20 Sept. 2000

Pages:188 - 196

[\[Abstract\]](#)
[\[PDF Full-Text \(648 KB\)\]](#)

IEEE CNF

**2 Practical lineage tracing in data warehouses***Cui, Y.; Widom, J.;*

Data Engineering, 2000. Proceedings. 16th International Conference on , 29 March 2000

Pages:367 - 378

[\[Abstract\]](#)
[\[PDF Full-Text \(192 KB\)\]](#)

IEEE CNF

**3 Making views self-maintainable for data warehousing***Quass, D.; Gupta, A.; Mumick, I.S.; Widom, J.;*

Parallel and Distributed Information Systems, 1996., Fourth International Conference on , 18-20 Dec. 1996

Pages:158 - 169

[\[Abstract\]](#)
[\[PDF Full-Text \(1228 KB\)\]](#)

IEEE CNF

**4 Materialized view design and maintenance in a financial data warehouse system***Lee, J.W.T.; Xiang Ye;*

Systems, Man, and Cybernetics, 1999. IEEE SMC '99 Conference Proceedings IEEE International Conference on , Volume: 5 , 12-15 Oct. 1999

Pages:930 - 935 vol.5

[\[Abstract\]](#) [\[PDF Full-Text \(384 KB\)\]](#) IEEE CNF

---

**5 History-less checking of dynamic integrity constraints**

*Chomicki, J.;*

Data Engineering, 1992. Proceedings. Eighth International Conference on , 2-Feb. 1992

Pages:557 - 564

[\[Abstract\]](#) [\[PDF Full-Text \(644 KB\)\]](#) IEEE CNF

---

[Home](#) | [Log-out](#) | [Journals](#) | [Conference Proceedings](#) | [Standards](#) | [Search by Author](#) | [Basic Search](#) | [Advanced Search](#) | [Join IEEE](#) | [Web Account](#) | [New this week](#) | [OPAC Linking Information](#) | [Your Feedback](#) | [Technical Support](#) | [Email Alerting](#) | [No Robots Please](#) | [Release Notes](#) | [IEEE Online Publications](#) | [Help](#) | [FAQ](#) | [Terms](#) | [Back to Top](#)

Copyright © 2004 IEEE — All rights reserved

- ☐ Home
- ☐ What Can I Access?
- ☐ Log-out

## Tables of Contents

- ☐ Journals & Magazines
- ☐ Conference Proceedings
- ☐ Standards

## Search

- ☐ By Author
- ☐ Basic
- ☐ Advanced

## Member Services

- ☐ Join IEEE
- ☐ Establish IEEE Web Account
- ☐ Access the IEEE Member Digital Library

Your search matched **5** of **955082** documents.

A maximum of **5** results are displayed, **15** to a page, sorted by **Relevance** in **descending** order.

You may refine your search by editing the current search expression or entering a new one in the text box.

Then click **Search Again**.

materializ\* <paragraph> view <paragraph> tuple

[Search Again](#)

**Results:**

Journal or Magazine = **JNL** Conference = **CNF** Standard = **STD**

**1 Maintaining materialized views in distributed databases**

*Segev, A.; Park, J.;*

Data Engineering, 1989. Proceedings. Fifth International Conference on , 6-10 Feb. 1989

Page(s): 262 -270

[\[Abstract\]](#) [\[PDF Full-Text \(720 KB\)\]](#) **IEEE CNF**

**2 Concurrent maintenance of views using multiple versions**

*Kulkarni, S.; Mohania, M.;*

Database Engineering and Applications, 1999. IDEAS '99. International Symposium Proceedings , 2-4 Aug. 1999

Page(s): 254 -258

[\[Abstract\]](#) [\[PDF Full-Text \(52 KB\)\]](#) **IEEE CNF**

**3 Practical lineage tracing in data warehouses**

*Cui, Y.; Widom, J.;*

Data Engineering, 2000. Proceedings. 16th International Conference on , 29 Feb.-3 March 2000

Page(s): 367 -378

[\[Abstract\]](#) [\[PDF Full-Text \(192 KB\)\]](#) **IEEE CNF**

**4 Detecting and representing relevant Web deltas in WHOWEDA**

*Bhowmick, S.S.; Madria, S.K.; Wee Keong Ng;*

Knowledge and Data Engineering, IEEE Transactions on , Volume: 15

Issue: 2 , March-April 2003

Page(s): 423 -441

[\[Abstract\]](#) [\[PDF Full-Text \(2779 KB\)\]](#) **IEEE JNL**

---

### 5 Updating distributed materialized views

*Segev, A.; Park, J.;*

Knowledge and Data Engineering, IEEE Transactions on , Volume: 1

Issue: 2 , June 1989

Page(s): 173 -184

[\[Abstract\]](#) [\[PDF Full-Text \(1128 KB\)\]](#) **IEEE JNL**

---

[Home](#) | [Log-out](#) | [Journals](#) | [Conference Proceedings](#) | [Standards](#) | [Search by Author](#) | [Basic Search](#) | [Advanced Search](#)  
[Join IEEE](#) | [Web Account](#) | [New this week](#) | [OPAC Linking Information](#) | [Your Feedback](#) | [Technical Support](#) | [Email Alerting](#)  
[No Robots Please](#) | [Release Notes](#) | [IEEE Online Publications](#) | [Help](#) | [FAQ](#) | [Terms](#) | [Back to Top](#)

Copyright © 2003 IEEE — All rights reserved